


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,841	BEENAU ET AL.	
	Examiner	Art Unit	
	Nam V. Nguyen	2635	

SEARCHED			
Class	Subclass	Date	Examiner
340	5.53	1/25/2006	NN
340	5.2	1/25/2006	NN
340	5.4+	1/25/2006	NN
340	5.52	1/25/2006	NN
340	5.6+	1/25/2006	NN
340	5.7	1/25/2006	NN
340	5.82	1/25/2006	NN
340	10.1	1/25/2006	NN
340	10.4-10.5	1/25/2006	NN
340	439	1/25/2006	NN
701	29	1/25/2006	NN
235	379-380	1/25/2006	NN
235	492	1/25/2006	NN
705	35,54,76	1/25/2006	NN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Search EAST: USPAT; US-PUB; EPO JPO, and Derwent	1/25/2006	NN